

Device Modeling Report

COMPONENTS: BIPOLAR JUNCTION TRANSISTOR
PART NUMBER: 2SC3150
MANUFACTURER: SANYO

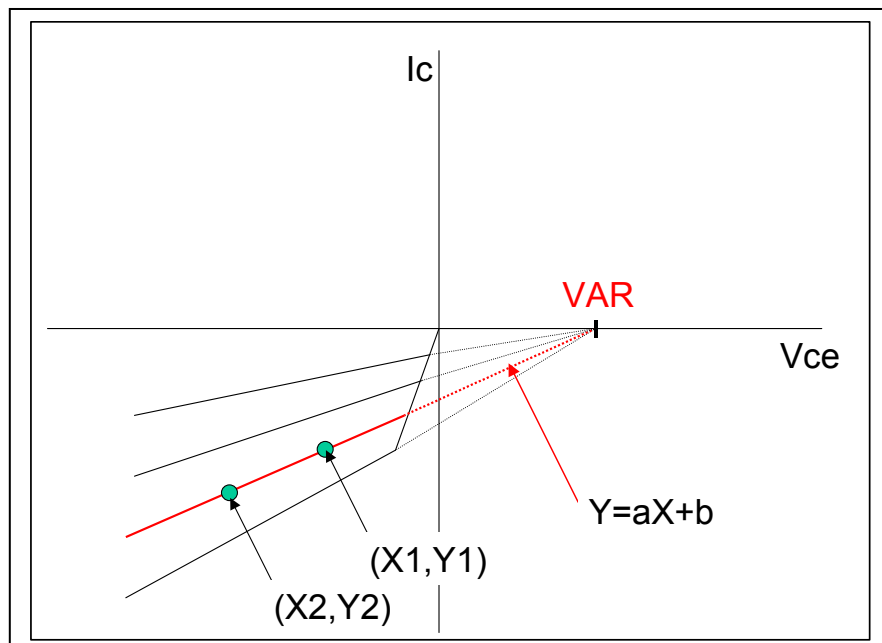
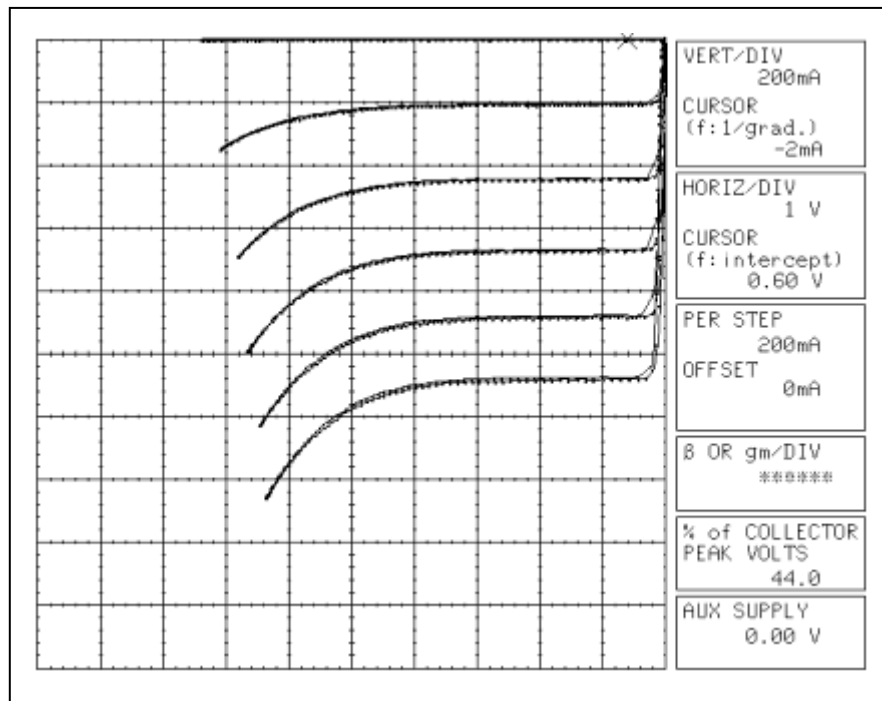


Bee Technologies Inc.

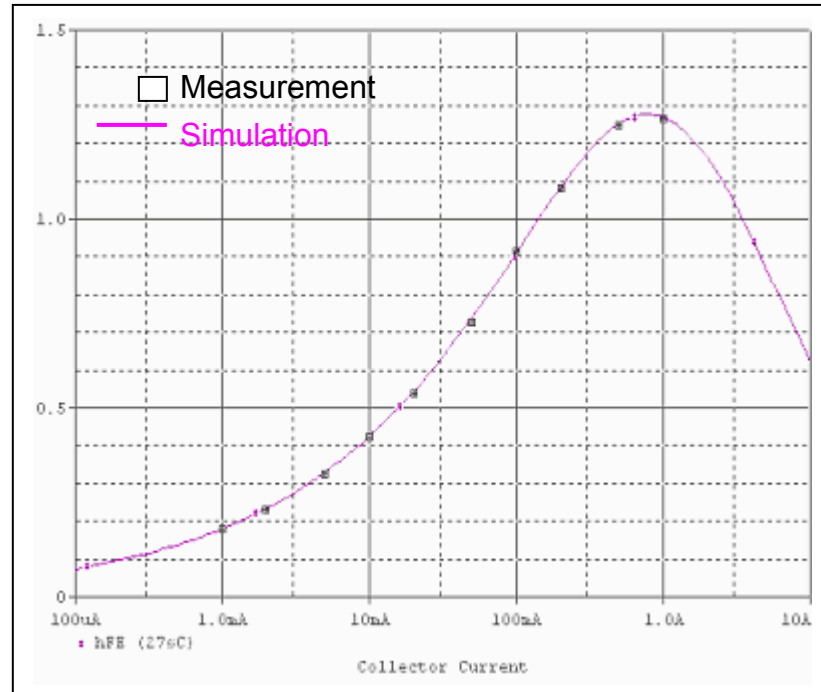
| PSpice model parameter | Model description |
|------------------------|---|
| IS | Saturation Current |
| BF | Ideal Maximum Forward Beta |
| NF | Forward Current Emission Coefficient |
| VAF | Forward Early Voltage |
| IKF | Forward Beta Roll-off Knee Current |
| ISE | Non-ideal Base-Emitter Diode Saturation Current |
| NE | Non-ideal Base-Emitter Diode Emission Coefficient |
| BR | Ideal Maximum Reverse Beta |
| NR | Reverse Emission Coefficient |
| VAR | Reverse Early Voltage |
| IKR | Reverse Beta Roll-off Knee Current |
| ISC | Non-ideal Base-Collector Diode Saturation Current |
| NC | Non-ideal Base-Collector Diode Emission Coefficient |
| NK | Forward Beta Roll-off Slope Exponent |
| RE | Emitter Resistance |
| RB | Base Resistance |
| RC | Series Collector Resistance |
| CJE | Zero-bias Emitter-Base Junction Capacitance |
| VJE | Emitter-Base Junction Potential |
| MJE | Emitter-Base Junction Grading Coefficient |
| CJC | Zero-bias Collector-Base Junction Capacitance |
| VJC | Collector-base Junction Potential |
| MJC | Collector-base Junction Grading Coefficient |
| FC | Coefficient for Onset of Forward-bias Depletion Capacitance |
| TF | Forward Transit Time |
| XTF | Coefficient for TF Dependency on Vce |
| VTF | Voltage for TF Dependency on Vce |
| ITF | Current for TF Dependency on Ic |
| PTF | Excess Phase at $f=1/2\pi \cdot TF$ |
| TR | Reverse Transit Time |
| EG | Activation Energy |
| XTB | Forward Beta Temperature Coefficient |
| XTI | Temperature Coefficient for IS |

Reverse

Reverse Early Voltage Characteristic

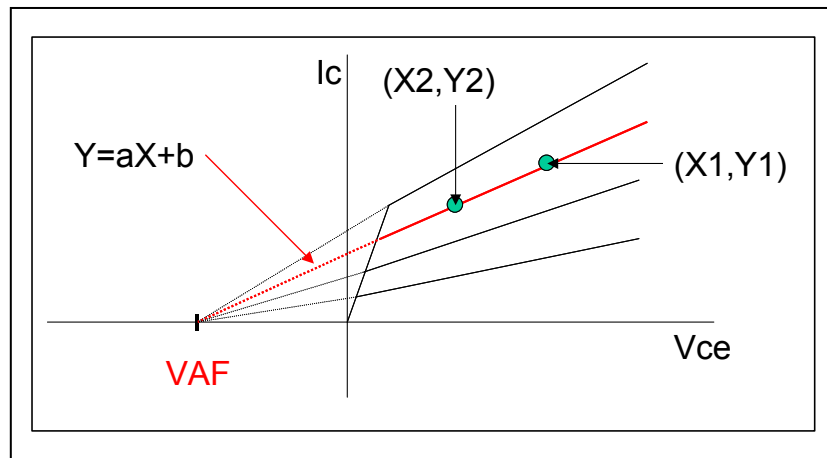
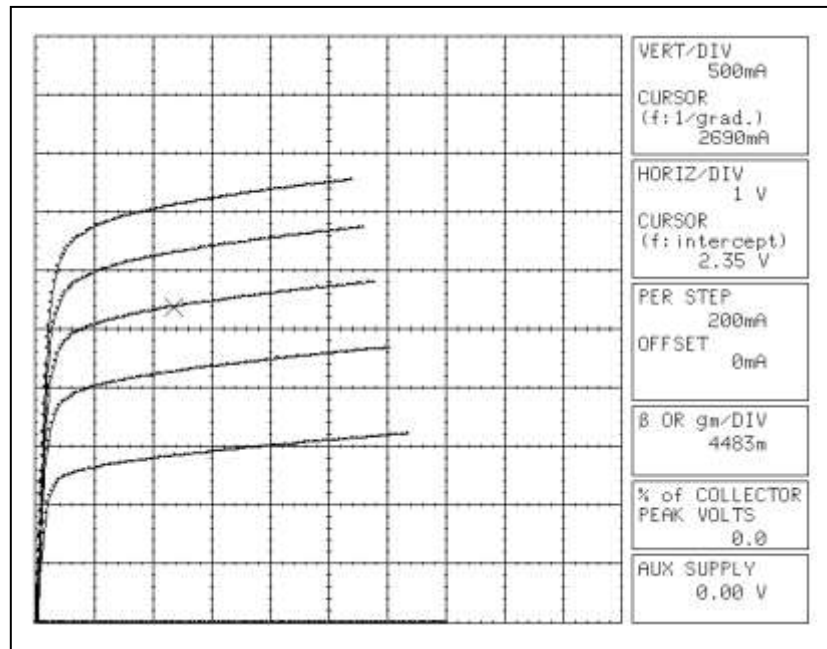


Reverse DC Beta Characteristic (I_e vs. h_{FE})

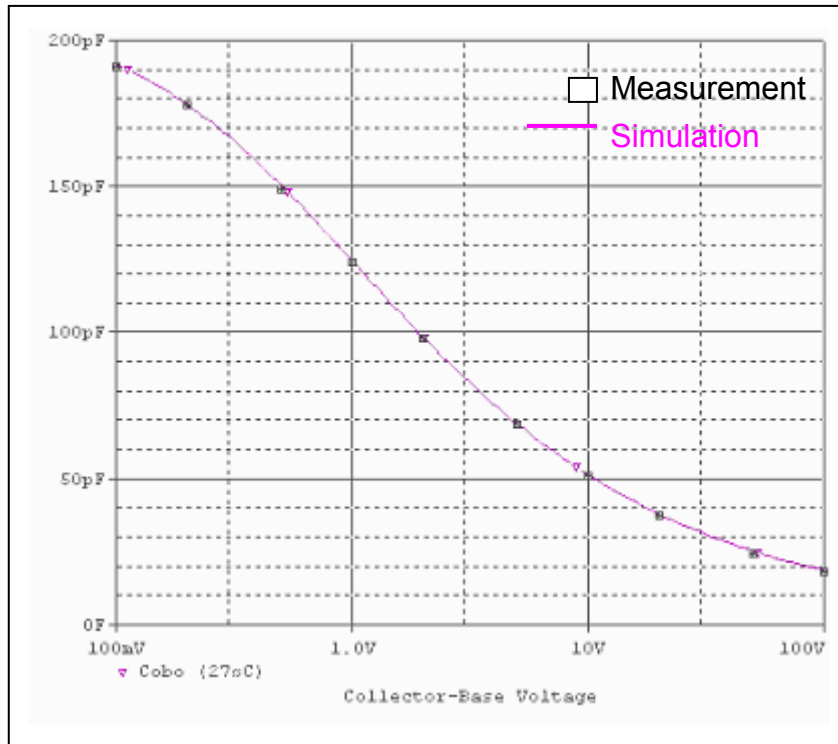


Forward

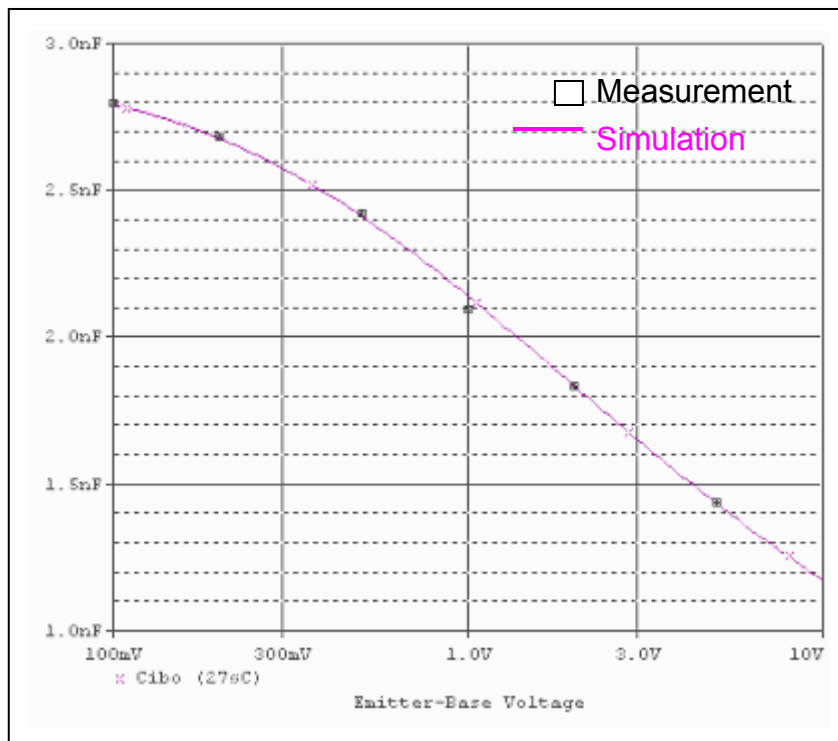
Forward Early Voltage Characteristic



C-B Capacitance Characteristic

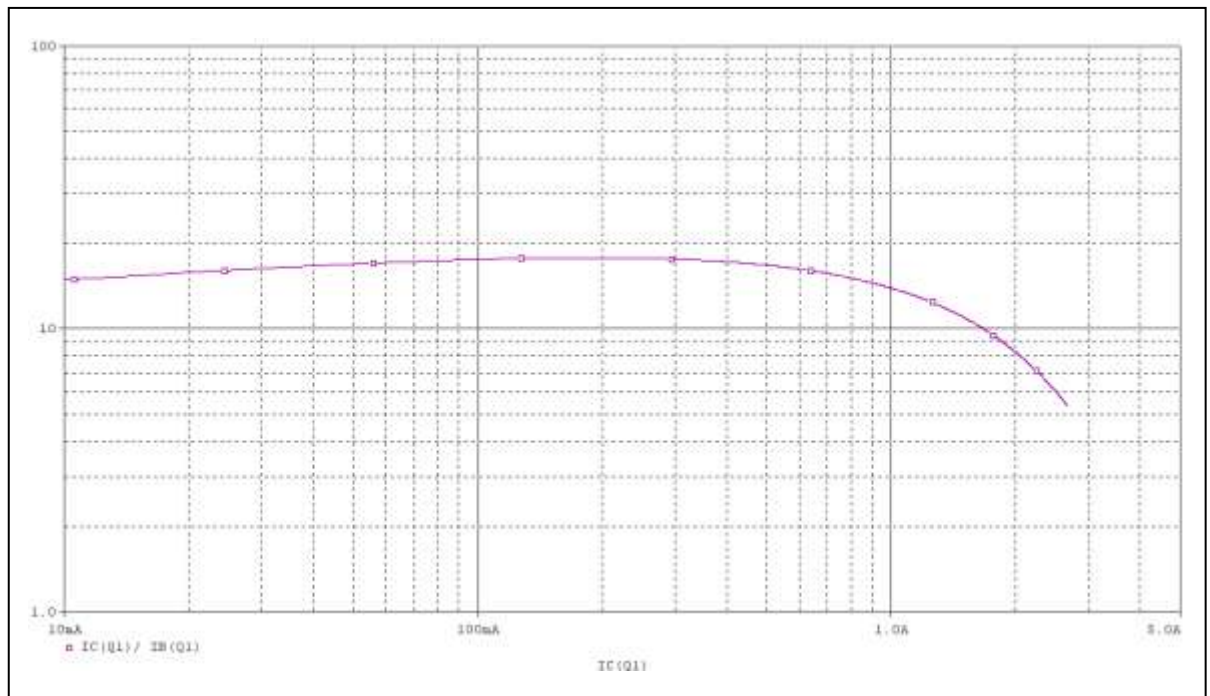


E-B Capacitance Characteristic

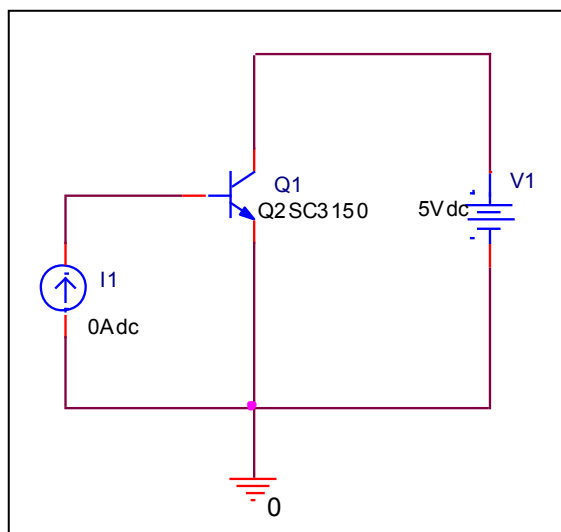


BJT Ic-hFE Characteristics

Circuit simulation result

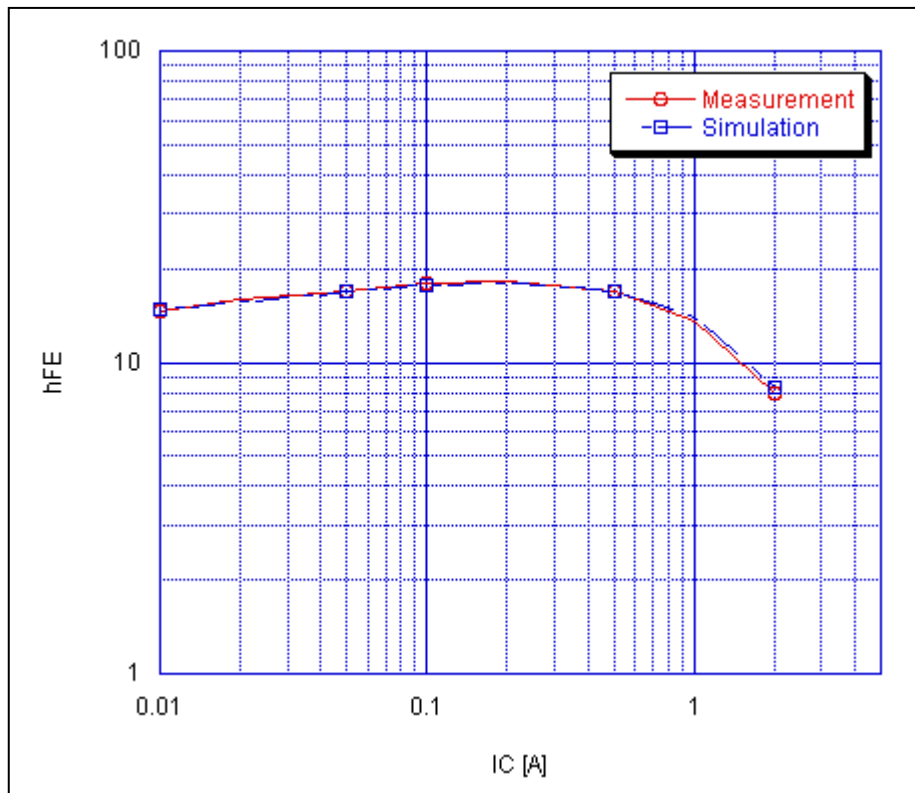


Evaluation circuit



Comparison Graph

Circuit simulation result

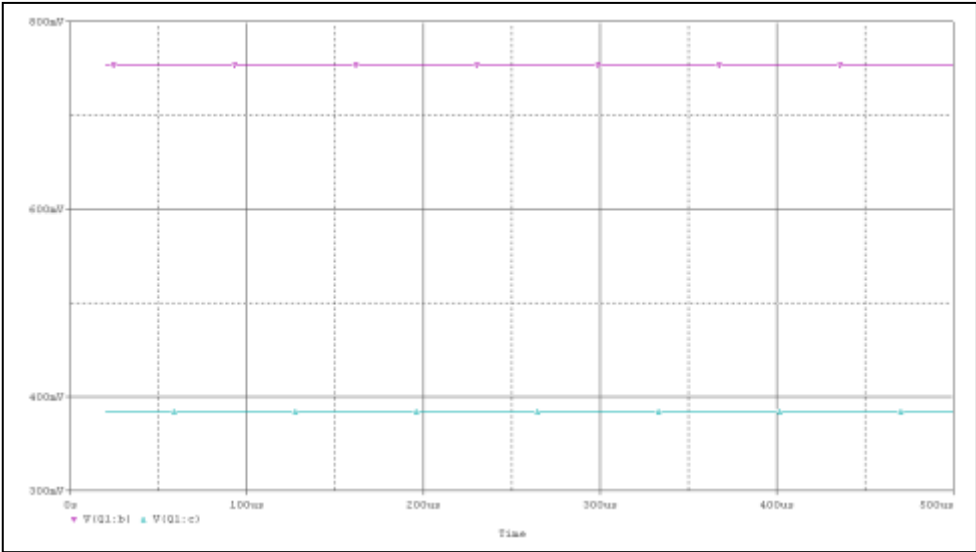


Simulation result

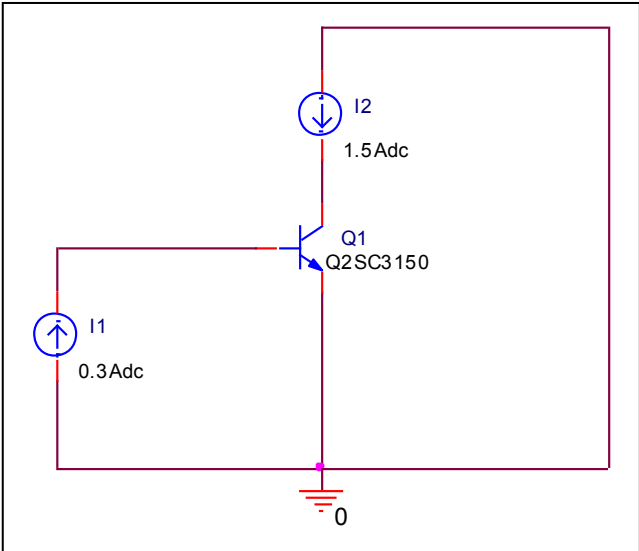
| Ic(A) | hFE | | %Error |
|-------|-------------|------------|----------|
| | Measurement | Simulation | |
| 0.01 | 14.5 | 14.709 | 1.441379 |
| 0.02 | 16 | 15.818 | 1.1375 |
| 0.05 | 17 | 16.955 | 0.264706 |
| 0.1 | 18 | 17.603 | 2.205556 |
| 0.2 | 18.3 | 17.847 | 2.47541 |
| 0.5 | 17 | 16.804 | 1.152941 |
| 1 | 13.5 | 13.941 | 3.266667 |
| 2 | 8 | 8.2927 | 3.65875 |

BJT Vce(sat) voltage & Vbe(sat) voltage Characteristics

Circuit simulation result



Evaluation circuit



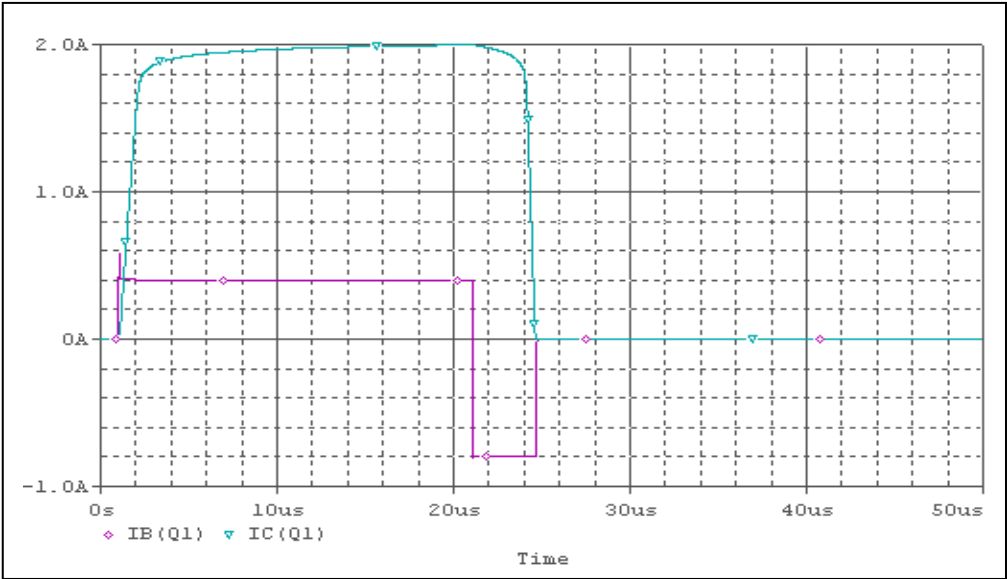
Simulation result

Test condition: $I_C/I_B = 5$, $I_C=1.5A$

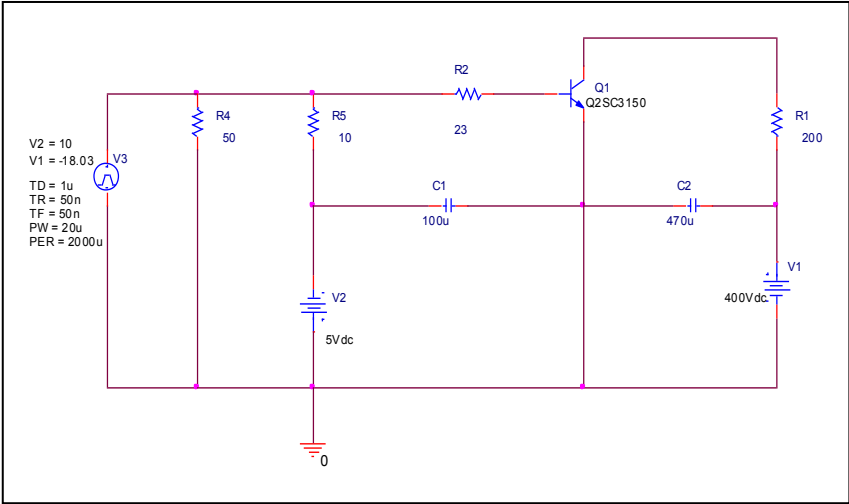
| Vce(sat)(V) | | | Vbe(sat)(V) | | |
|-------------|------------|----------|-------------|------------|----------|
| Measurement | Simulation | Error(%) | Measurement | Simulation | Error(%) |
| 0.38 | 0.384 | 1.0526 | 0.76 | 0.753 | 0.921 |

Switching Characteristics

Circuit simulation result



Evaluation circuit

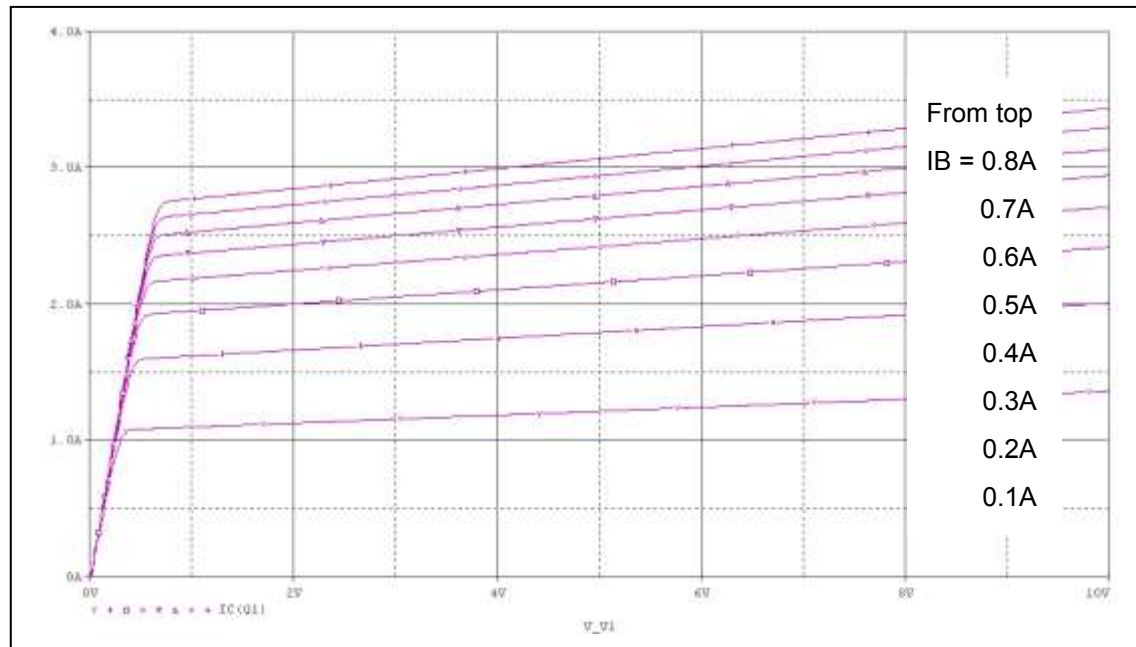


Simulation result

| Ts(us) | | | Tf(us) | | |
|-------------|------------|--------|-------------|------------|--------|
| Measurement | Simulation | %Error | Measurement | Simulation | %Error |
| 3 | 2.9673 | 0.9 | 0.7 | 0.67 | 4.2857 |

Output Characteristics

Circuit simulation result



Evaluation circuit

